

INTERNATIONAL STANDARD

NORME INTERNATIONALE



**Semiconductor devices –
Part 3: Discrete devices: Signal, switching and regulator diodes**

**Dispositifs à semiconducteurs –
Partie 3: Dispositifs discrets: Diodes de signal, diodes de commutation et diodes
régulatrices**



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CONTENTS

FOREWORD.....	4
1 Scope.....	6
2 Normative references	6
3 Terms, definitions and graphical symbols	6
3.1 Signal and switching diodes	6
3.2 Voltage reference diodes and voltage regulator diodes.....	7
3.3 Current-regulator diodes.....	8
4 Letter symbols	9
4.1 General	9
4.2 Signal and switching diodes	9
4.2.1 Subscripts	9
4.2.2 List of letter symbols.....	9
4.3 Voltage reference diodes and voltage regulator diodes.....	10
4.3.1 Subscripts	10
4.3.2 List of letter symbols.....	10
4.4 Current-regulator diodes.....	10
4.4.1 Subscripts	10
4.4.2 List of letter symbols.....	11
5 Essential ratings and characteristics.....	11
5.1 General	11
5.2 Signal and switching diodes	11
5.2.1 Ratings (limiting values)	11
5.2.2 Characteristics	11
5.3 Voltage reference diodes and voltage regulator diodes.....	14
5.3.1 Ratings (limiting values)	14
5.3.2 Characteristics	14
5.4 Current-regulator diodes.....	16
5.4.1 Ratings (limiting values)	16
5.4.2 Characteristics	16
6 Measuring methods	17
6.1 General	17
6.2 Signal and switching diodes	17
6.2.1 Reverse current I_R	17
6.2.2 Forward voltage V_F	17
6.2.3 Total capacitance C_{tot}	18
6.2.4 Forward recovery time t_{fr} and peak forward recovery voltage V_{FRM}	19
6.2.5 Reverse recovery time (t_{rr}) and recovered charge (Q_r).....	20
6.2.6 Detector voltage efficiency η_V	21
6.2.7 Detector power efficiency η_P	22
6.2.8 Noise V_n , I_n	23
6.3 Voltage reference diodes and voltage regulator diodes.....	24
6.3.1 Working voltage V_Z	24
6.3.2 Differential resistance in the working current range r_Z	25
6.3.3 Temperature coefficient of working voltage α_{VZ}	25
6.3.4 Reverse current I_R	26
6.3.5 Forward voltage V_F	26

6.3.6	Junction capacitance C_{tot}	26
6.3.7	Noise voltage V_n	26
6.4	Current-regulator diodes.....	27
6.4.1	Regulator current I_S	27
6.4.2	Temperature coefficient of regulator current α_{I_S}	27
6.4.3	Regulator current variation ΔI_S	28
6.4.4	Limiting voltage V_L	28
6.4.5	Small-signal regulator conductance g_S	29
6.4.6	Knee conductance g_k	31
7	Acceptance and reliability.....	31
7.1	Acceptance-defining characteristics.....	31
7.2	Electrical endurance tests.....	33
Figure 1	– Current-regulator diode graphical symbol.....	8
Figure 2	– Current-regulator diode characteristic with symbol identification.....	10
Figure 3	– Reverse recovery current waveform.....	12
Figure 4	– Current and voltage waveforms.....	13
Figure 5	– Circuit diagram for the measurement of I_R	17
Figure 6	– Circuit diagram for the measurement of V_F	18
Figure 7	– Circuit diagram for the measurement for C_{tot}	18
Figure 8	– Circuit diagram for the measurement of t_{fr} and V_{FRM}	19
Figure 9	– Circuit diagram for the measurement of t_{rr}	20
Figure 10	– Circuit diagram for the measurement of η_V	21
Figure 11	– Circuit diagram for the measurement of η_p	22
Figure 12	– Circuit diagram for the measurement of noise current.....	23
Figure 13	– Circuit diagram for the measurement of V_Z	24
Figure 14	– Circuit diagram for the measurement of V_n	26
Figure 15	– Circuit diagram for the measurement of I_S	27
Figure 16	– Circuit diagram for the measurement of g_S (two-voltmeter method).....	29
Figure 17	– Circuit diagram for the measurement of g_S (two-terminal bridge method).....	30
Table 1	– Preferred reference diode working voltages – Voltages in the E24 series.....	14
Table 2	– Preferred reference diode working voltages – Voltages in the E12 series.....	15
Table 3	– Acceptance-defining characteristics for acceptance after endurance tests.....	32
Table 4	– Test circuits and conditions for the endurance tests.....	33

INTERNATIONAL ELECTROTECHNICAL COMMISSION

SEMICONDUCTOR DEVICES –**Part 3: Discrete devices: Signal, switching and regulator diodes**

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International Standard IEC 60747-3 has been prepared by subcommittee 47E: Discrete semiconductor devices, of IEC technical committee 47: Semiconductor devices.

This second edition cancels and replaces the first edition published in 1985, Amendment 1:1991 and Amendment 2:1993. This edition constitutes a technical revision.

This edition includes the following significant technical changes with respect to the previous edition:

- a) All clauses were re-edited to latest IEC publication format and style with all contents from previous publication.
- b) All clauses have been amended by suitable additions and deletions.

This standard is to be read in conjunction with IEC 60747-1:2006 and its Amendment 1 (2010).

The text of this standard is based on the following documents:

FDIS	Report on voting
47E/453/FDIS	47E/455/RVD

Full information on the voting for the approval of this standard can be found in the report on voting indicated in the above table.

This publication has been drafted in accordance with the ISO/IEC Directives, Part 2.

A list of all parts in the IEC 60747 series, published under the general title *Semiconductor devices*, can be found on the IEC website.

Future standards in this series will carry the new general title as cited above. Titles of existing standards in this series will be updated at the time of the next edition.

The committee has decided that the contents of this publication will remain unchanged until the stability date indicated on the IEC web site under "<http://webstore.iec.ch>" in the data related to the specific publication. At this date, the publication will be

- reconfirmed,
- withdrawn,
- replaced by a revised edition, or
- amended.

SEMICONDUCTOR DEVICES –

Part 3: Discrete devices: Signal, switching and regulator diodes

1 Scope

This part of IEC 60747 gives the requirements for the following devices:

- signal diodes (excluding diodes designed to operate at frequencies above several hundred MHz);
- switching diodes (excluding high power rectifier diodes);
- voltage-regulator diodes;
- voltage-reference diodes;
- current-regulator diodes.

2 Normative references

The following documents, in whole or in part, are normatively referenced in this document and are indispensable for its application. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

IEC 60050 (all parts), *International Electrotechnical Vocabulary*
(available at <<http://www.electropedia.org>>)

IEC 60747-1:2006, *Semiconductor devices – Part 1: General*
Amendment 1:2010

3 Terms, definitions and graphical symbols

For the purposes of this document, the terms and definitions given in IEC 60050-521, IEC 60050-702 and IEC 60747-1, and the following, apply.

3.1 Signal and switching diodes

3.1.1

forward recovery voltage

V_{FR}

forward voltage occurring during the forward recovery time after switching from zero or a reverse voltage to a forward current

3.1.2

detector voltage efficiency

η_v

ratio of the d.c. load voltage to the peak sinusoidal input voltage under specified circuit conditions